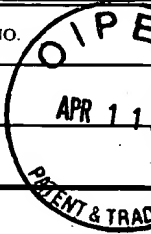


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1299		SERIAL NO. 09/428,125	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					FILING DATE October 26, 1999		GROUP 2822	
U.S. PATENT DOCUMENTS								
*Examiner Initial	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
KR		5,411,912	5-2-95	Sakamoto				
	AB	5,508,221	4-16-96	Kamiyama				
	AC	5,876,788	3-2-99	Bronner				
	AD	6,010,931	1-4-00	Sun et al.				
	AE	6,037,205	3-14-00	Huh et al.				
	AF	6,048,764	4-11-00	Suzuki et al.				
	AG	6,150,208	11-21-00	Deboer et al.				
	AH	6,150,706	11-21-00	Thakur et al.				
	AI	6,168,985	1-2-01	Asano et al.				
	AJ	6,180,481	1-30-01	DeBoer				
H	AK	6,197,653	3-6-01	Khamankar				
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
KR	AM	407161827A		Japan				
KR	AN	405211288A		Japan				
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER <i>A. Rose</i>					DATE CONSIDERED <i>6/12/03</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

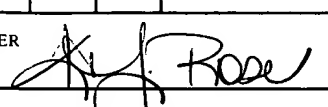
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1299	SERIAL NO. 09/428,125
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.	
				FILING DATE October 26, 1999	GROUP 2822



U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RR	AA	5,834,060	11-1998	Kawahara et al.			
	AB	5,760,474	06-1998	Schuele			
	AC	5,864,496	01-1999	Mueller et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
RR	AM	04162527A	06-1992	Japan			
RR	AN	403209869A	09-1991	Japan			
	AO						
	AP						
	AQ						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
*Examiner Initial	AR	Van Zant, "Microchip Fabrication: A Practical Guide to Semiconductor Processing" 4 th Edition, McGraw Hill 2000, pgs. 388-389.	
	AS		
	AT		

EXAMINER 	DATE CONSIDERED 6/12/03
---	----------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.